Αναγνώριση Προτύπων: Ενοποιημένη παρουσίαση και σύγχρονες τάσεις Σέργιος Θεοδωρίδης Καθηγητής Τμήματος Πληροφορικής και Τηλεπικοινωνιών Πανεπιστημίου Αθηνών

- Στην ομιλία αυτή γίνεται μία ενοποιημένη παρουσίαση διαφόρων τεχνικών και μεθόδων Αναγνώρισης Προτύπων τόσο για την περίπτωση εκπαίδευσης με επίβλεψη (supervised) όσο και για την περίπτωση εκπαίδεσυης χωρίς επίβλεψη (unsupervised). Η ομιλία εστιάζει σε όλες τις φάσεις σχεδιασμού ενός συστήματος αναγνώρισης προτύπων, όπως γένεση χαρακτηριστικών, επιλογή χαρακτηριστικών, σχεδιασμό ταξινομητών και τέλος στην αξιολόγηση του συστήματος.
- Η ομιλία εστιάζει στις πλέον σύγχρονες τεχνικές σχεδιασμού ταξινομητών, όπως Support Vector Machines και τεχνικές γένεσης χαρακτηριστικών βασισμένων σε Independent Component Analysis.
 Επίσης, παρουσιάζονται και πιο κλασσικές μεθοδολογίες που χρησιμοποιούνται σήμερα για ανάκτηση δεδομένων με βάση το περιεχόμενο (content based retrieval), όπως Δυναμική Στρέβλωση και Κρυφά Μαρκοβιανά μοντέλα (Hidden Markov Models).

PATTERN RECOGNITION REVIEW AND RECENT TRENDS

SERGIOS THEODORIDIS Dept. of Informatics and Telecommunications Univ. of Athens What is Pattern Recognition?

 Pattern Recognition is the Scientific Discipline whose goal is the classification of objects into a number of classes or categories.

Depending on the application these objects can be

> Images

Speech waveforms

> Any measurement set need to be classified The objects to be classified are known as Patterns. - Typical Applications Machine Vision OCR **Computer Aided Diagnosis Speech Recognition** Data Base Retrieval (PRBMS) **Remote Sensing Bioinformatics Data Mining**

Supervised versus Unsupervised Pattern Recognition

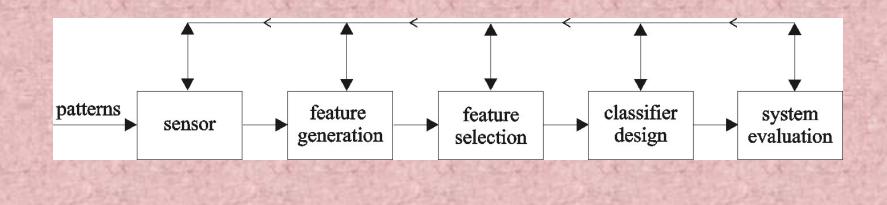
Supervised PR : The number of classes are known to the PR-system designer

A set of training data is available and the class label of each one of the data points is known

Unsupervised PR or Clustering : There is no training data set with known class labels

Data have to be clustered (grouped) together by unraveling similarities among them

• A Pattern Recognition system



Feature Generation Stage

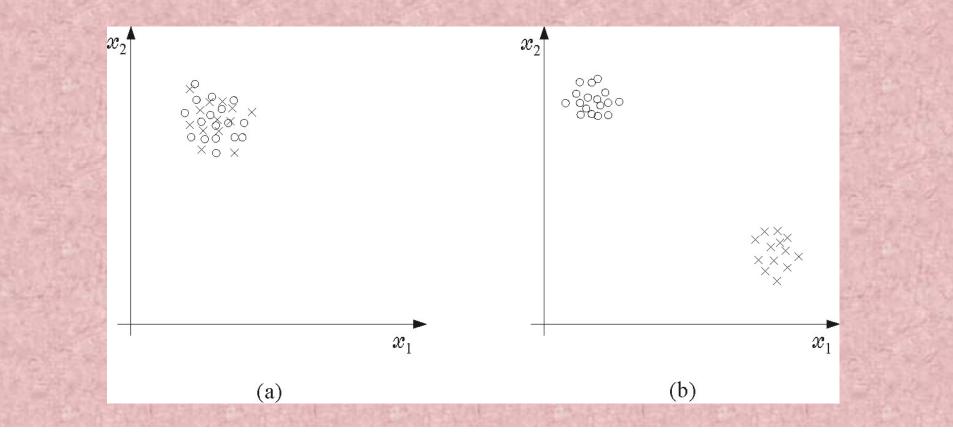
Features : Measurable quantities, each carrying information that can be used for the classification task.

A large number of features, xi, i=1, 2, ... L, can be generated during this stage.

Some of them may convey no discriminative information and have to discarded

Some may convey discriminative information, but to a varying degree Feature Selection Stage

During this stage, from the large number of features generated in the previous stage, select the "best", i.e., the most informative ones, from the class discrimination point of view.

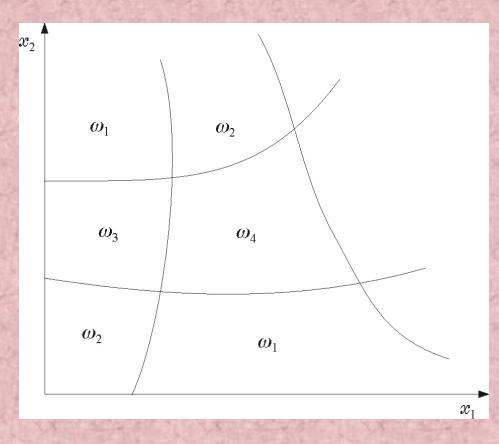


Select the "best" number l. This is a very crucial stage. A bad choice of the l and / or the best features, results in bad performance, irrespective of the classifier design stage

Classifier Design Stage
 Form Feature vectors from the 1 selected features

 $\underline{\mathbf{x}} = \begin{bmatrix} \mathbf{x}_1, \mathbf{x}_2, \dots, \mathbf{x}_1 \end{bmatrix}^{\mathrm{T}} \in \mathbb{R}^1$

Partition the feature space into regions. Each region is associated with a single class.

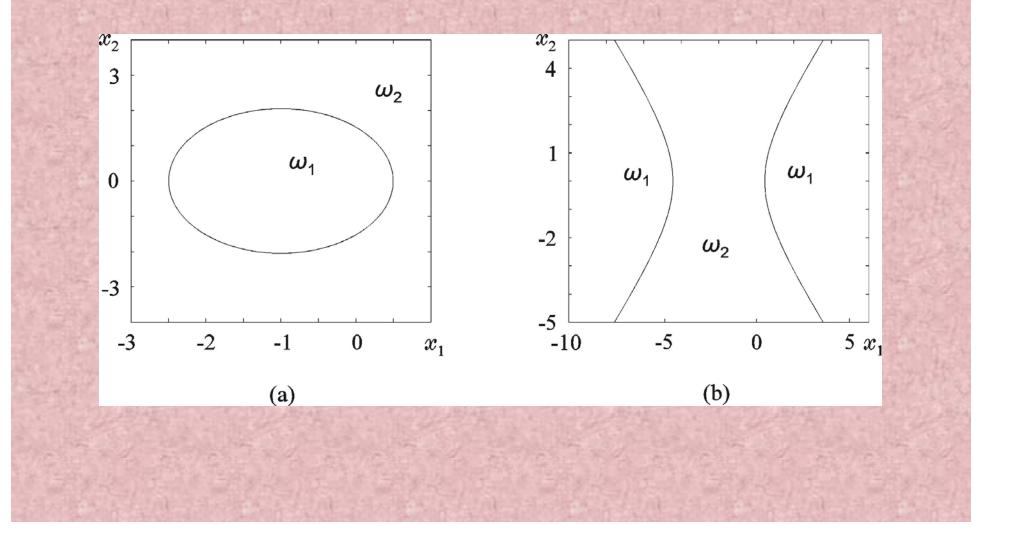


The (hyper)Surfaces that partition the space are known as Decision Surfaces System Validation

Estimate the error probability of the designed PR system • Classifier Design - Bayesian Classifier > For an M-class task assign $\underline{x} \rightarrow \omega_i$: $\underset{i}{\operatorname{arg\,max} P(\omega_i \mid \underline{x}) = \underset{i}{\operatorname{arg\,max} P(\omega_i)P(x \mid \omega_i)}$

The Bayesian classifier is optimum, i.e. Minimizes the Error Probability

> If All $p(\underline{x} | \omega_i)$ are normal, then the Decision Hypersurfaces are quadrics



•k-Nearest Neighbor Classifier

- The steps :

• 1) Choose k

 2) From the training set xi, i=1, 2, ... N find the k nearest neighbors to <u>x</u>. Assign <u>x</u> to the class with the highest number ki among k

B

As
$$N \rightarrow \infty$$

 $P_B \leq P_{KNN} \leq P_B + \frac{1}{\sqrt{kl}}$
> For the simplest k=1
 $P_B \leq P_{NN} \leq 2I$

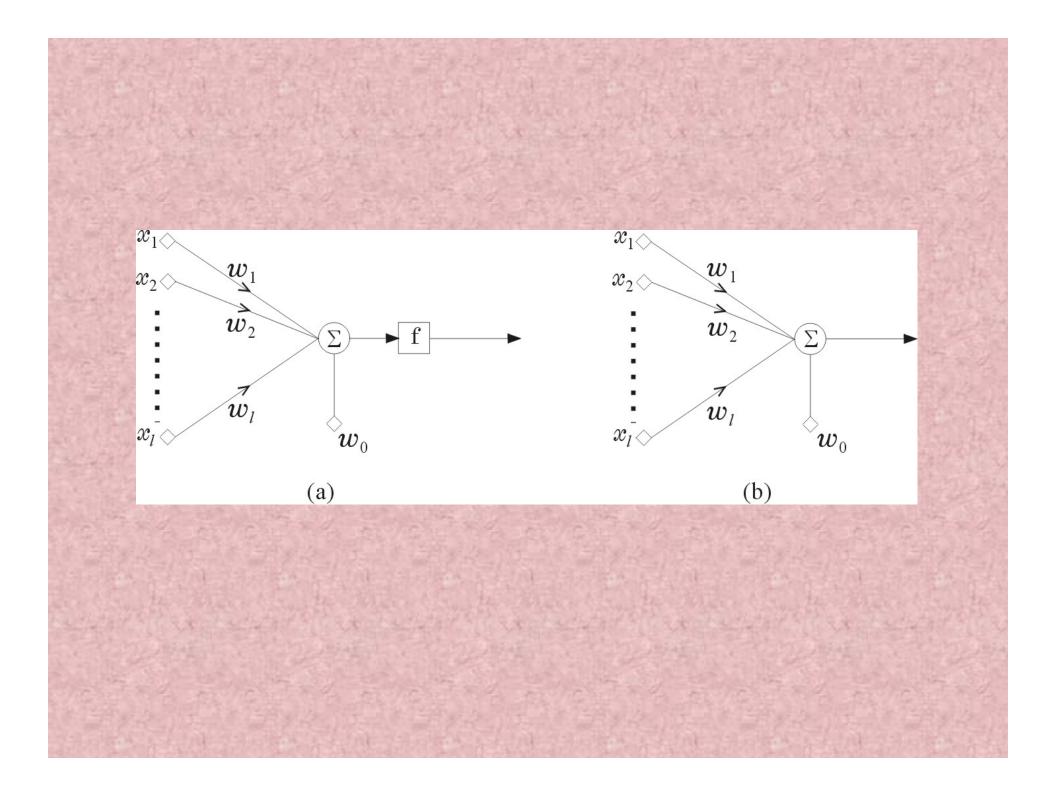
Linear Classifiers

- **The goal** : Partition the feature space via hyperplanes. That is, for each ω_i define a linear discriminant function fi(x)
- Assign \underline{x} to ω_i $\omega_i : \underset{i}{\operatorname{arg\,max}} f_i(\underline{x})$

- Decision surfaces are of the form

$$\underline{w}^{T} \underline{x} + w_{0} = 0$$

The Perceptron Assume classes linearly separable Cost function $J(\underline{w}) = \sum_{\underline{x} \in Y} \delta_{\underline{x}} \underline{w}^{T} \underline{x}$ The algorithm $\underline{\mathbf{w}}(t+1) = \underline{\mathbf{w}}(t) - \rho_t \sum \delta_x \underline{\mathbf{x}}$ (Y set of misclassified training pattern by w) Converges in finite number of steps



Support Vector Machines

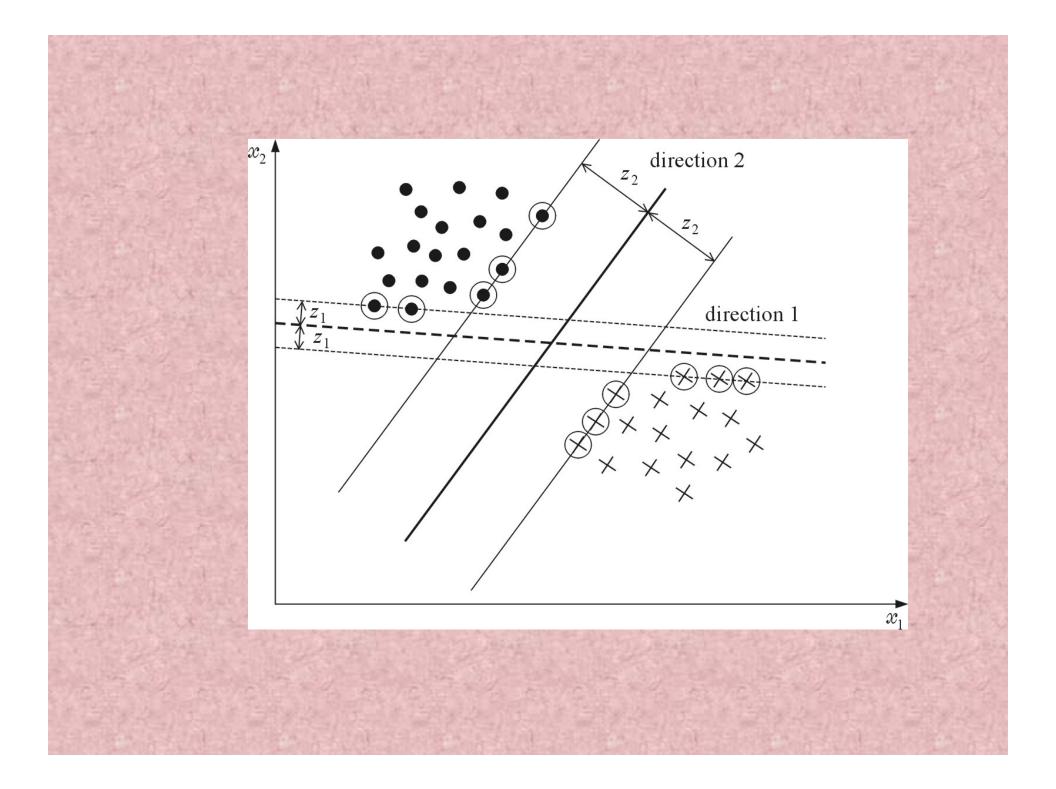
The goal : Design the linear classifier that leaves the maximum margin from both classes (separable case)

minimize

$$\mathbf{J}(\mathbf{w}) = \frac{1}{2} \|\mathbf{w}\|^2$$

subject to :

 $y_{i} \left(w^{T} \underline{x}_{i} + w_{0} \right) \geq 1, i = 1, 2, ..., N$ $y_{i} = \begin{cases} 1 & \underline{x} \in \omega_{1} \\ -1 & \underline{x} \in \omega_{2} \end{cases}$



> The solution :

$$g(\underline{x}) \equiv \underline{w}^{T} \cdot \underline{x} + w_{0}$$
$$= \sum_{i=1}^{N_{s}} \lambda_{i} y_{i} \underline{x}_{i}^{T} \underline{x} + w$$

λi : Lagrange multipliers
 Ns : Number of Support vectors from the training set

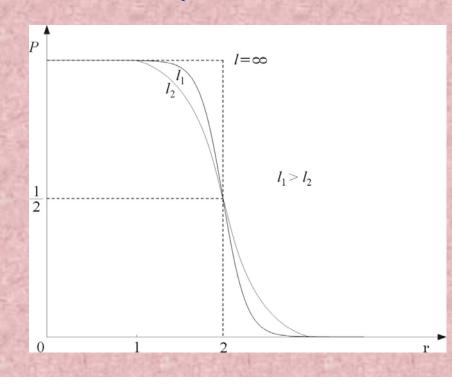
The task is a quadratic convex optimization problem with linear inequality constraints.

It guarantees good generalization properties

Nonlinear Classifiers

Capacity of the 1-dimensional space in linear dichotomies

$$P_{N}^{1} = \begin{cases} \frac{1}{2^{N-1}} \sum_{i=0}^{l} {N-1 \choose i} & N > l+1 \\ 1 & N \le l+1 \end{cases}$$

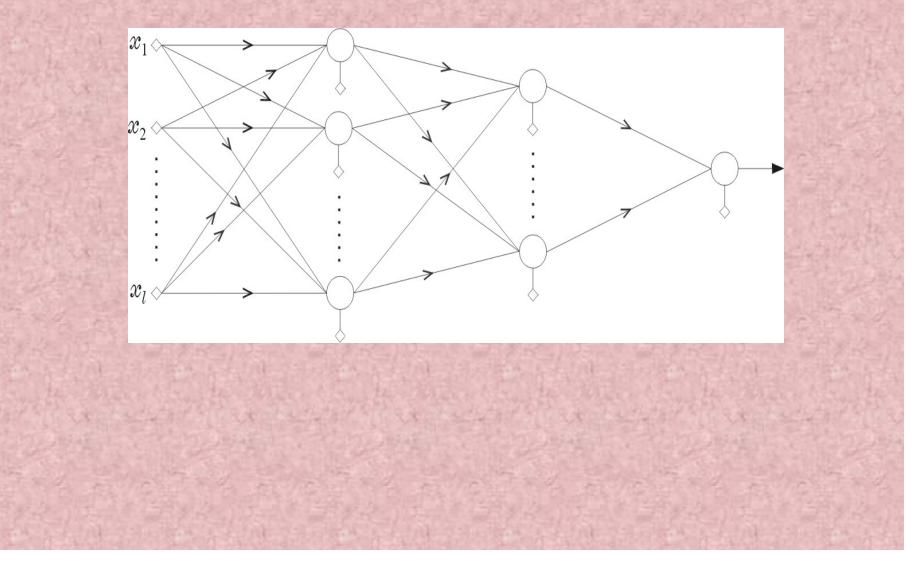


Given N points, then mapping into a higher dimensional space

$R^1 \rightarrow R^k, k > l$

increases the probability of locating the N points so that to be linearly separable.

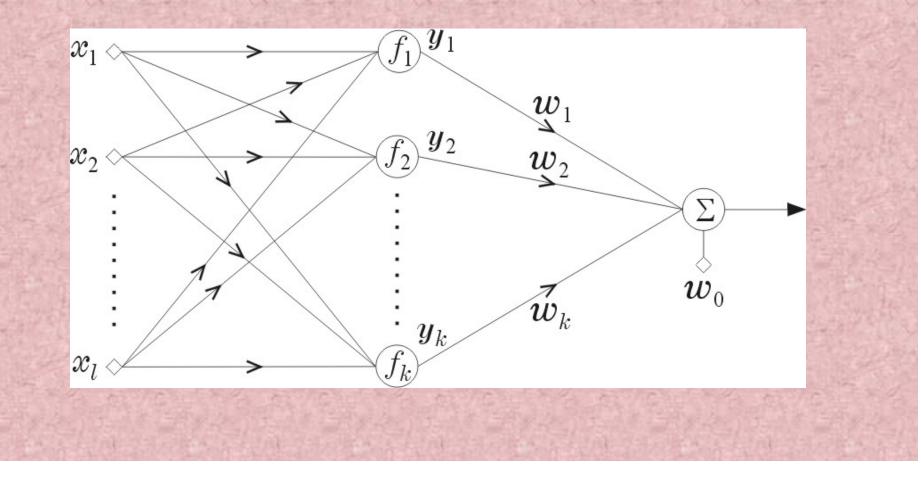
- The Multilayer Perceptron



Generalized linear Classifiers > Define the mapping $\underline{x} \in \mathbb{R}^{1} \rightarrow \underline{y} \in \mathbb{R}^{k}$ $\underline{y} = [f_{1}(\underline{x}), f_{2}(\underline{x}), ..., f_{k}(\underline{x})]^{T}$

Design a linear classifier in the new space

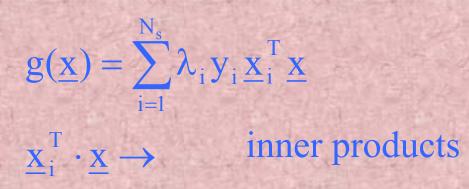
$$g(\underline{x}) = W_0 + \sum_{i=1}^{k} W_i f_i(\underline{x})$$



Radial Basis Classifiers $f_i(x) = \exp\left(-\frac{\left\|\underline{x} - \underline{c}_i\right\|^2}{2\sigma_i^2}\right)$

Universal Aproximators:

Multilayer perceptrons with sigmoid functions and RBF networks can arbitrarily approximate any nonlinear function. Nonlinear Support Vector Machines
> Remember from the linear case



Choose the mapping $\underline{x} \in \mathbb{R}^{1} \xrightarrow{\Phi} \underline{y} \in \mathbb{R}^{k}$ So that $\sum \underline{\Phi}_{r}(\underline{x}) \underline{\Phi}_{r}(\underline{z}) = K(\underline{x}, \underline{z})$

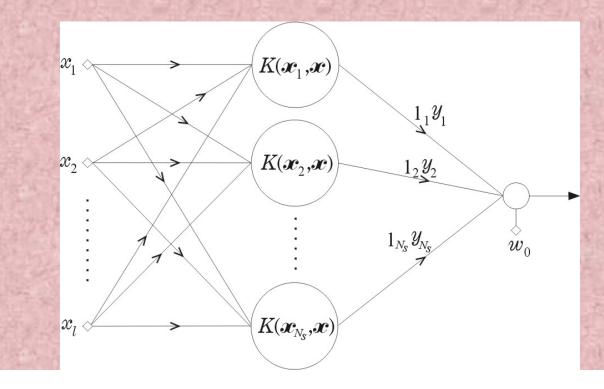
That is, inner products in the high dimensional space are expressed in terms of a Kernel function of the input low dimensional space.

The above is guaranteed by Mercer's theorem, for a class of kernel functions

 $\underline{\mathbf{x}} = \begin{bmatrix} \mathbf{x}_1, \mathbf{x}_2 \end{bmatrix}^{\mathrm{T}} \in \mathbb{R}^2 \rightarrow \begin{bmatrix} \mathbf{x}_1^2 \\ \sqrt{2}\mathbf{x}_1\mathbf{x}_2 \\ \mathbf{x}_2^2 \end{bmatrix} \equiv \underline{\mathbf{y}} \in \mathbb{R}^3$

 $\underline{\mathbf{y}}_{i}^{\mathrm{T}} \underline{\mathbf{y}}_{j} = (\underline{\mathbf{x}}_{i}^{\mathrm{T}} \underline{\mathbf{x}}_{j})^{2}$

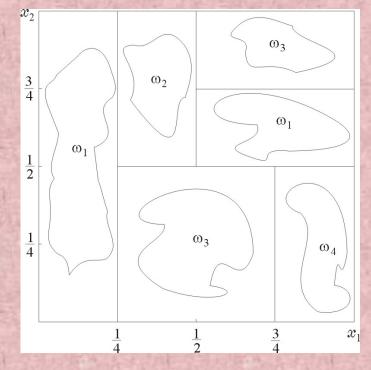
Example:



Decision Trees

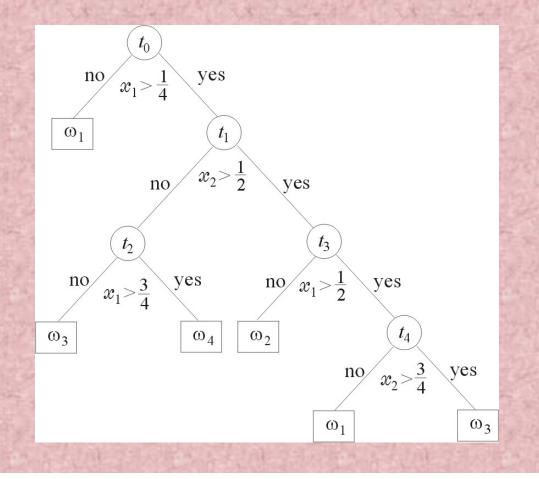
These are Multistage decision systems in which classes are sequentially rejected until we reach into a finally accepted class.

Feature Space is split into regions in a sequential manner



Decisions / rejections are performed by applying a sequence of questions applied to individual features xi, i=1, 2, ..., 1

Is feature xi $\leq \alpha$??

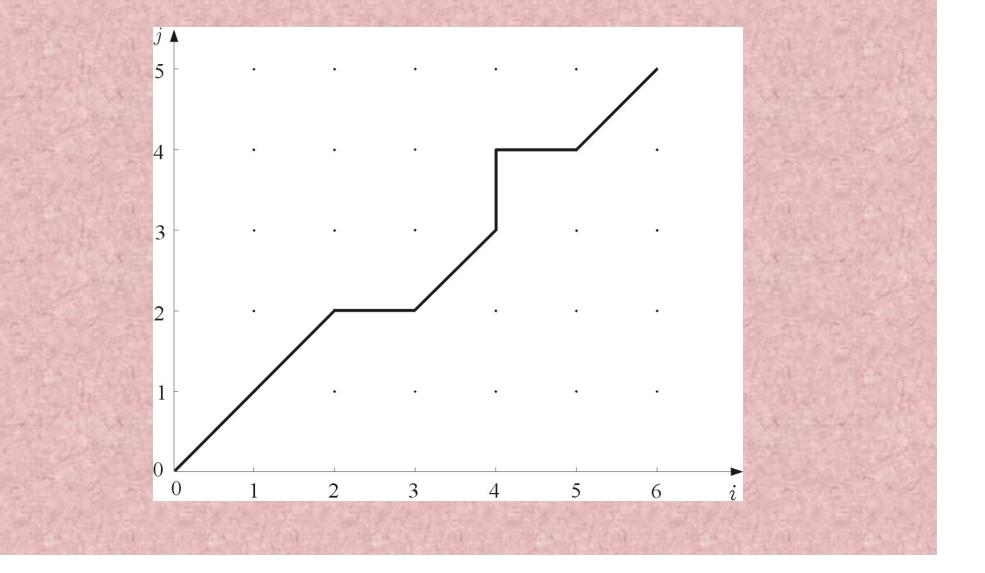


-Template Matching:

Each class is represented by a single reference pattern. An unknown pattern is classified to a class, according to its "similarity" to the corresponding reference pattern.

A Similarity Measure, or Matching Cost must first be defined.

 Optimal path searching techniques.
 Each pattern is represented by a sequence of feature vectors Reference pattern $\Rightarrow \underline{r}(i), i = 1, 2, ... I$ Unknown pattern $\Rightarrow \underline{t}(j), j = 1, 2, ... J$



Construct ALL possible paths through the grid For each point (i,j) of the grid define a cost, e.g. $d(i,j) = \left\|\underline{r}(i) - \underline{t}(j)\right\|$

Similarity between two patterns is defined as the total cost of the optimal path

$$D = \sum_{k=0}^{K-1} d(i_k, j_k)$$

That is D minimum

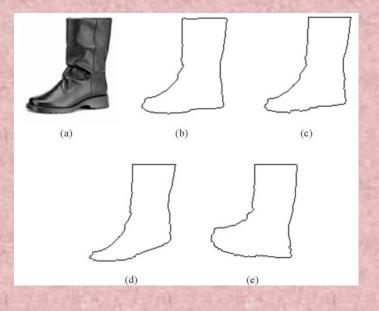
> Typical Examples :

EDIT distance for matching written wordsDynamic Time Warping

Deformable Template Matching

The philosophy : The reference and test patterns very often do not look exactly the same. Thus, allow this to be accommodated in the similarity measure.

Create deformed variants of the original reference pattern (prototype)



The Steps :

. Adopt a parametric transformation to deform the reference prototype $T_{\xi}[\underline{r}]$. Adopt a cost that measures disimilarity

between the test pattern and the deformed

 $E_{m}(\underline{\xi}):\underline{t}\leftrightarrow T_{\xi}[\underline{r}]$

Adopt a cost the measures deformation energy, i.e. dissimilarity between \underline{r} , $\underline{T\xi}[\underline{r}]$ $E_d(\underline{\xi}): \underline{r} \leftrightarrow T_{\xi}[\underline{r}]$

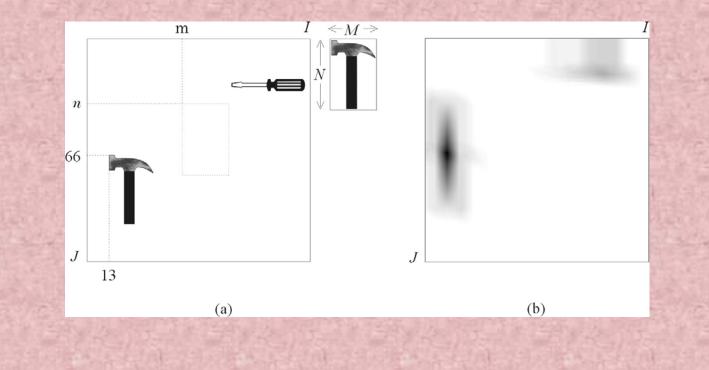
Choose ξ : $\underline{\xi}: \min_{\underline{\xi}} \left[E_m(\underline{\xi}) + E_d(\underline{\xi}) \right]$

Best matching cost between \underline{t} and \underline{r} : $E_{m}(\underline{\xi}_{min}) + E_{d}(\underline{\xi}_{min})$

Correlation Measures

The Goal : Given a block of recorded data find if a specific known reference pattern is contained and where it is located.

Compute the correlation between the test pattern and the reference pattern and find the maximum



Context Dependent Classification

The task : A number N of patterns $\underline{x}_1,..,\underline{x}_N$, is given for classification to a set of classes $\omega_1, \omega_2, ..., \omega_M$. However classes are NOT independent. Assigning a pattern \underline{x}_i to a class depends

• On its own value <u>x</u>i

> On the values of the other patterns \underline{x}_i , $i \neq j$

[>] On the existing relation among the classes

- For the sequence of patterns $X : \underline{x}_1, \underline{x}_2, ..., \underline{x}_N$ and M possible classes, there is a total of M^N possible sequences of corresponding classes;

> $Ω_i : ω_{i_1}, ω_{i_2}, ..., ω_{i_N}$ i = 1,2,..., M^N

where

 $\underline{\mathbf{x}}_{\mathbf{i}}$ is assigned to $\boldsymbol{\omega}_{\mathbf{i}_{\mathbf{k}}}$

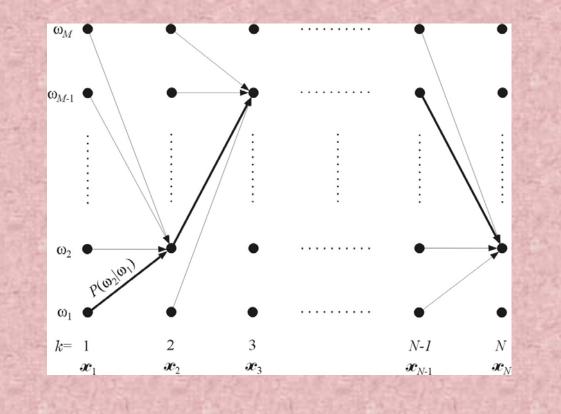
 $\omega_{i_k} \in \{1, 2, \dots, M\}$

-Bayesian Classification

Assign x : to Ω_i : arg max P($\Omega_i | X$) Complexity very high for computing the maximum The Viterbi Algorithm

Assume a Markovian class dependence model

$$P(\omega_{i_{k}} | \omega_{i_{k-1}}, \omega_{i_{k-2}}, ..., \omega_{i_{1}}) = P(\omega_{i_{k}} | \omega_{i_{k-1}})$$



Applications

Channel Equalization, where classes are related to states

Hidden Markov Modeling

Feature Generation

A problem dependent stage. Typical directions for generating features:

- Statistical

Moments
Parametric models (AR, ARMA)
Fractal dimension

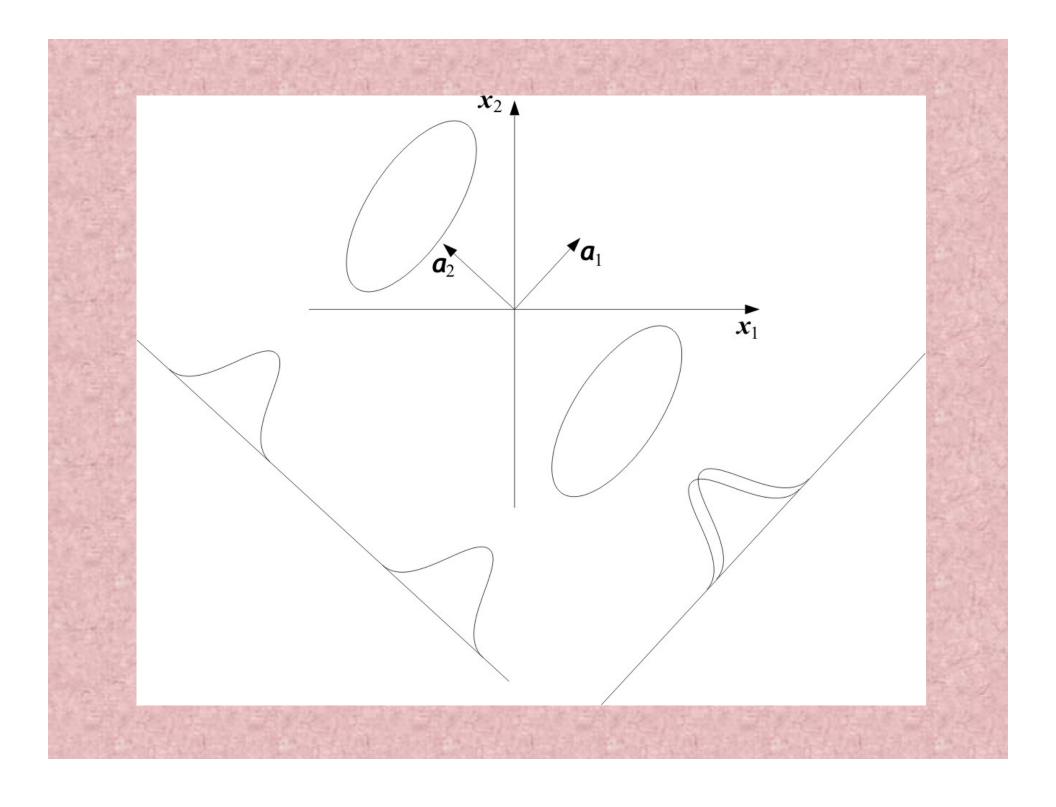
Geometric Perimeter Curvature Transform based features Fourier Transforms DCT, DST Wavelet transforms Principal Component Analysis (PCA) **Singular Value Decomposition** Independent Component Analysis (ICA) Principal Component Analysis (PCA) Generate, from data vector X, mutually uncorrelated features $\mathbf{y} = \mathbf{A}^{\mathrm{T}} \mathbf{x}$ $E[y_i y_j] = \delta_{ij}, i, j = 1, 2, ..., N$ The above is fulfilled if A is chosen to have the eigenvectors, $\underline{a}_i, i = 1, 2, \dots, N$, of $\mathbf{R}_{\mathbf{x}} = \mathbf{E}[\mathbf{x}\mathbf{x}^{\mathsf{T}}]$ as its columns.

. Choose $y_i, i = 1, 2, ..., m < N$, to correspond to the m largest eigenvalues

.Then

$$\hat{\underline{x}} = \sum_{i=1}^{m} y_i \underline{a}_i$$

is the MMSE approximation to \underline{X} .



Independent Component Analysis (ICA)

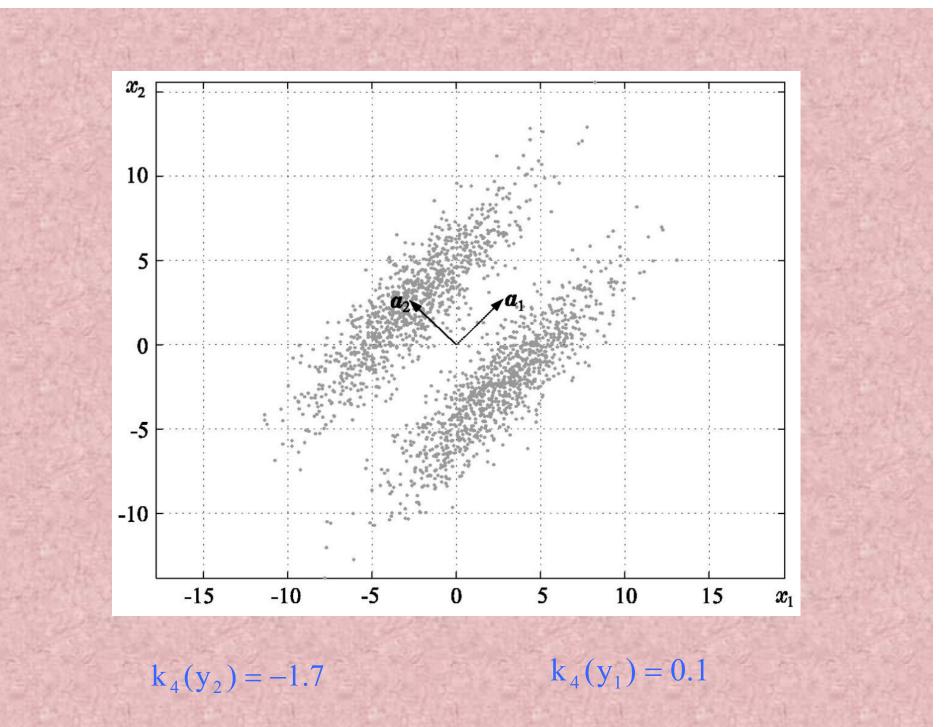
.Barlow's hypothesis: The outcome of the early processing performed in our visual cortical feature detectors might be the result of a redundancy reduction process.

The neural outputs are as independent as possible.
Given <u>x</u> produce y

 $\underline{y} = W \underline{x}$ so that y_i, y_j are as statistically independent as possible. .Higher-order statistics are required to ensure independence.
.Non-Gaussian processes must be assumed.
.The goal: Given N independent components y_i, i = 1,2,...,N, choose the 1 best ones.
.What is best?

The least resemblance to Gaussian, the better it is.
A Gaussian random process has all its higher-order cumulants identically zero.
The larger the absolute value of kurtosis (4th-order

cumulant), the less the resemblance to Gaussian.



Feature Selection

The goal: Select the l most informative features from the (large) set of generated ones. Two questions are involved.

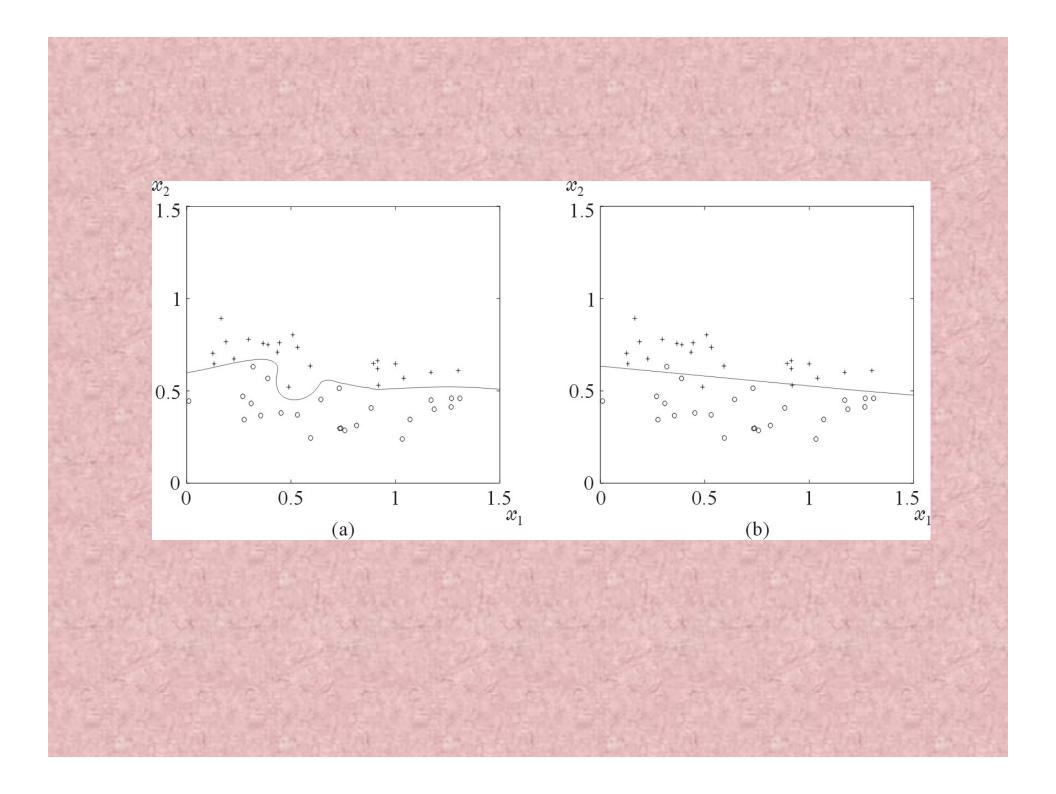
. What is the "optimal" number 1

. Which are the best I features

- Generalization Performance of a classifier: This refers to the capability of a classifier to perform well, when faced with data unknown to it, i.e., with data outside the training set.

For finite number N of training data > 1 affects the number of free parameters of a classifier. The number of free parameters must be large enough, w.r. to N, For the classifier to learn what makes "similar" the patterns *within* each class and what makes one class different from another small enough

Not to learn underlying differences among data of *same* class

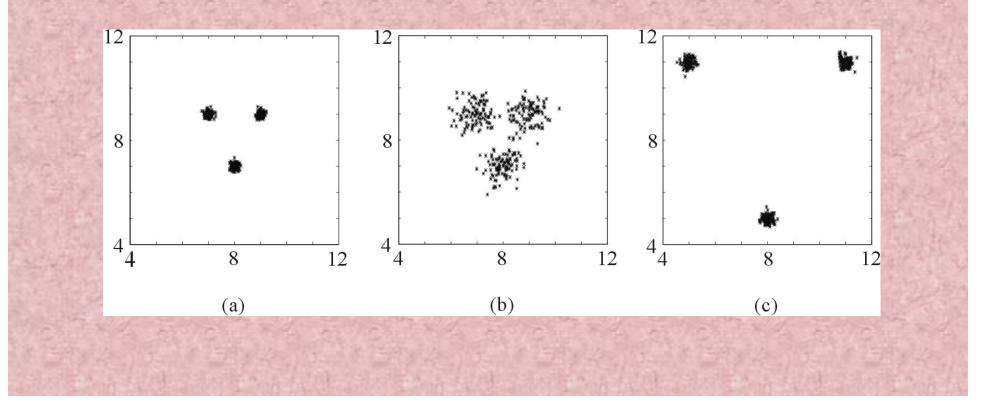


Vapnic - Chernovenkis bound and Vc dimension

- Let P_e^N be the empirical error based on the training data samples
- > Let P_e the true error
- [>] P_e^N is close enough to P_e with high probability provided N is large enough w.r to the V_c dimension

 V_c is a measure of the intrinsic capacity of a classifier and it is related to the maximum number of dichotomies the classifier can perform on N training points

An example : For a multilayer perceptron $2\left[\frac{k_{n}^{h}}{2}\right] l \leq V_{c} \leq 2k_{w} \log(ek_{n})$ 1 input space dimension $k^{h} \text{ number of hidden layer nodes}$ $k_{n} \text{ total number of nodes}$ $k_{w} \text{ total number of weights}$ How to select the best l features > Feature vectors must exhibit Large between - class distance Small within class variance



System evaluation

The error counting technique is adopted using a appropriately selected test set .

- A theoretically derived rule of thumb for the size L of the test set, for an error probability of P, is

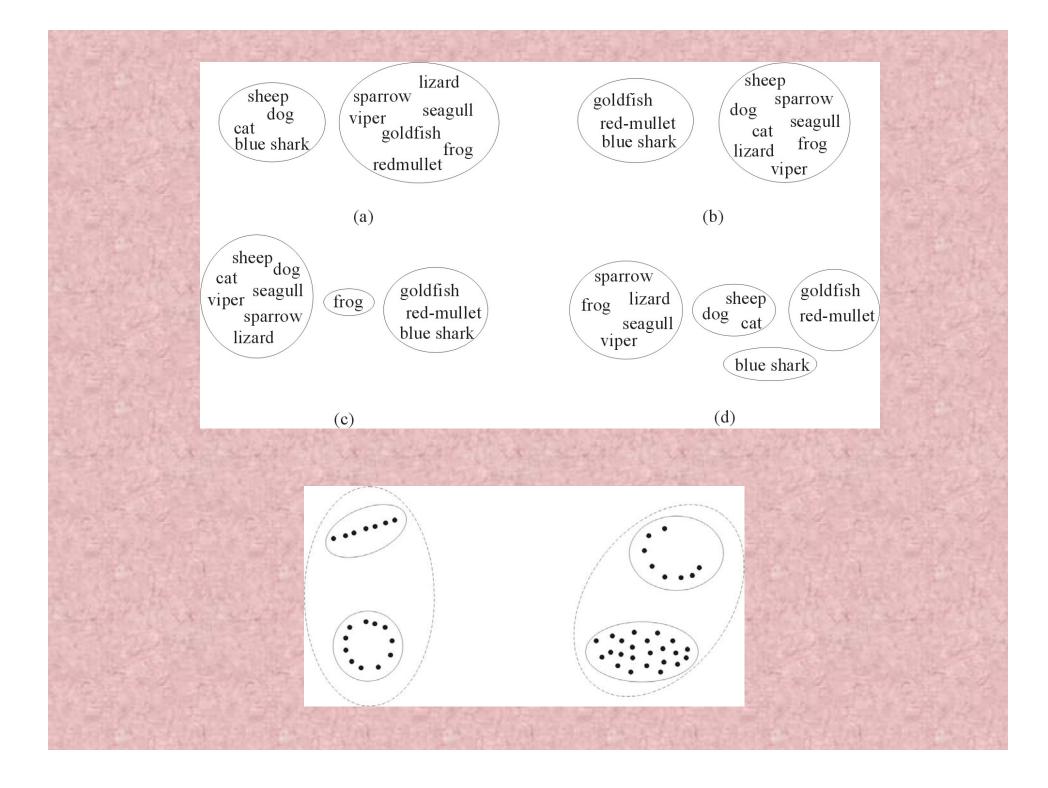
 $L \approx \frac{100}{P}$ For P=0.01, L=10 000, for P=0.03, L=3000 **The Holdout Method**: Divide the training set into two subsets. *One for training* the classifier and *one for testing* it.

– Leave-one-out method: From the N training points use N-1 for training and one for testing. Repeat this N times, each time with a different point for testing. This guarantees independence between training and testing. Count the errors and average them to obtain the error percentage.

Clustering

- The major task of clustering is to reveal the organization of patterns into sensible clusters

 Subjectivity is a reality one has to live with when dealing with clustering



Definitions of clustering

Given $X = \{\underline{x}_1, \underline{x}_2, ..., \underline{x}_N\}$ an m-clustering of X, is the partition of X into m sets, $C_1, C_2, ..., C_m$,

> $C_{i} \neq \emptyset \quad i = 1,..., m$ $\bigcup_{i=1}^{m} C_{i} = X$ $C_{i} \cap C_{j} = \emptyset, \quad i \neq j, \quad i, j = 1, 2,..., m$

Fuzzy clustering of X into m clusters is characterized by m membership function, u_i

> $u_{j}: X \to [0,1], j = 1,2,...,m$ $\sum_{j=1}^{m} u_{j}(x_{i}) = 1, i = 1,2,...,N$ $0 < \sum_{i=1}^{N} u_{j}(x_{i}) < N, j = 1,2,...,m$

To perform any clustering task the following steps are required

> Feature Selection : Features must be selected so that to encode as much information as possible

Proximity measure : A measure that quantifies the terms "similar" or "dissimilar"

Clustering Criterion : It depends on the interpretation the expert gives to the term "sensible". The criterion can be expressed via a cost.

Clustering Algorithm : Having adopted a proximity measure and a criterion, the algorithm will reveal the srtucture Validation of results

> Interpretation of results

Clustering Algorithms

The optimal way to partition X into m clusters is to consider ALL possible partitions and select the "best". This is an NP-hard problem

A clustering algorithm searches a small fraction of all possible partitions

Categories of clustering algorithms

Sequential : A *Single* clustering is produced. The data are presented sequentially, at least once

Hierarchical algorithms : A *sequence* of clusterings is recovered

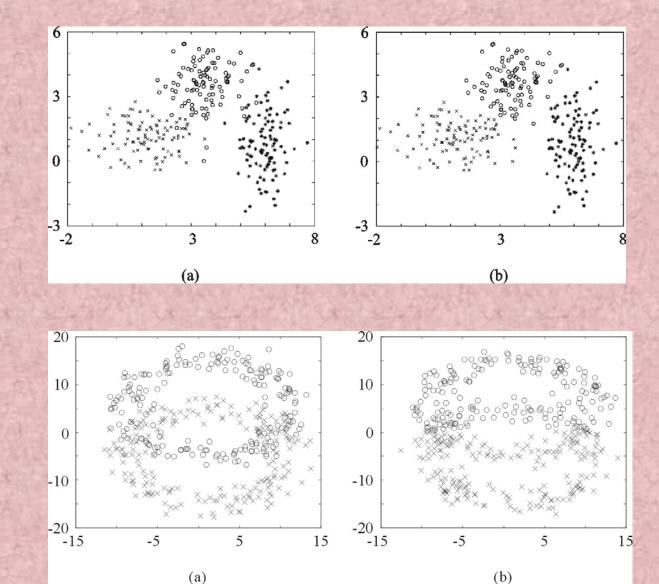
Agglomerative algorithms : The clusterings are obtained in a decreasing number of clusters at each step

Divisive : These act in the opposite direction

Algorithms based on cost function optimization Hard clustering algorithms **Fuzzy algorithms Possibilistic algorithms** Other Genetic Stochastic relaxation Competitive learning

Choice of the appropriate algorithm, similarity measure and clustering criterion depends on the specific problem

Example 1: Use of the Generalized Mixture **Decomposition Scheme**



(b)

Example 2 : Use of the Fuzzy Shell Clustering Scheme

